Scanning Probe Microscopy for Nanomaterials for Energy, Electrochemistry and Beyond

Scientific Workshop | 29 April

Agilent Technologies invites you to attend a special workshop being held Tuesday, 29 April, focusing on the latest techniques for electrical characterization at the nanoscale. This dynamic one-day event will be hosted by Peter Schön and Mark Huijben, SRO Program Directors 'Enabling Technologies' and 'Nanomaterials for Energy'. Scientists from both, academia and industry will deliver application-oriented presentations.

Research capabilities of Agilent's impressive new flagship AFM, the 7500, will also be highlighted during the workshop and attendees will have an opportunity to participate in a hands-on demo session at the end of the day. Designed to extend the frontier of atomic force microscopy, the 7500 achieves atomic-resolution imaging with a 90μm AFM closed-loop scanner, provides unrivaled environmental control and monitoring, and offers an unprecedented range of electrical characterization and electrochemistry capabilities.

Workshop Location
Twente University,
Building 'Carre' Lecture Room: 2L.
For route description please visit:
http://www.mtpgroup.nl/route-description.aspx

Date & Time
29.04.14 (Tuesday) at 9.00

Agenda

9.00 **Get Together**

9.15 **Welcome**
Michael Hippler (Agilent Technologies) and Peter Schön (University of Twente)

9.25 **Elucidating nanoscale electrocatalysis with electrochemical scanning probe techniques**
Stanley Lai (University of Twente)

10.05 **Conductivity and interface reactions of solid ion conductors**
Kerstin Schmale (University of Münster)

10.30 **Coffee Break**

11.00 **Electronic activation of metalloporphyrins for their reaction with oxygen in an environmentally controlled scanning tunnelling microscope**
Hans Elemans (Radboud University Nijmegen)

11.40 **Investigating trapped hydration layers between graphene and a hydrophilic substrate**
Dr. Tjeerd Bollmann (University of Twente)

12.20 **Break with Light Lunch**

1.00 **Light on Organic Photovoltaic Devices: The Key Role of Scanning**

Probe Microscopy
Philippe Leclère (University of Mons)

1.40 From Mechanical Mapping to Imaging: Other Tools from Agilent for the Nanoworld
Michael Hippler (Agilent Technologies)

2.10 The New High-Resolution Agilent 7500 SPM: Controlled Environment for the Investigation of Electrical Material Properties
Matthias Fenner (Agilent Technologies)

2.40 Live Demonstration: Agilent 7500

To register for this exciting and highly informative workshop, please contact Michael_Hippler@Agilent.com or Register Here

We look forward to seeing you soon!